

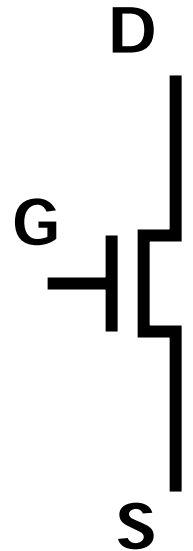
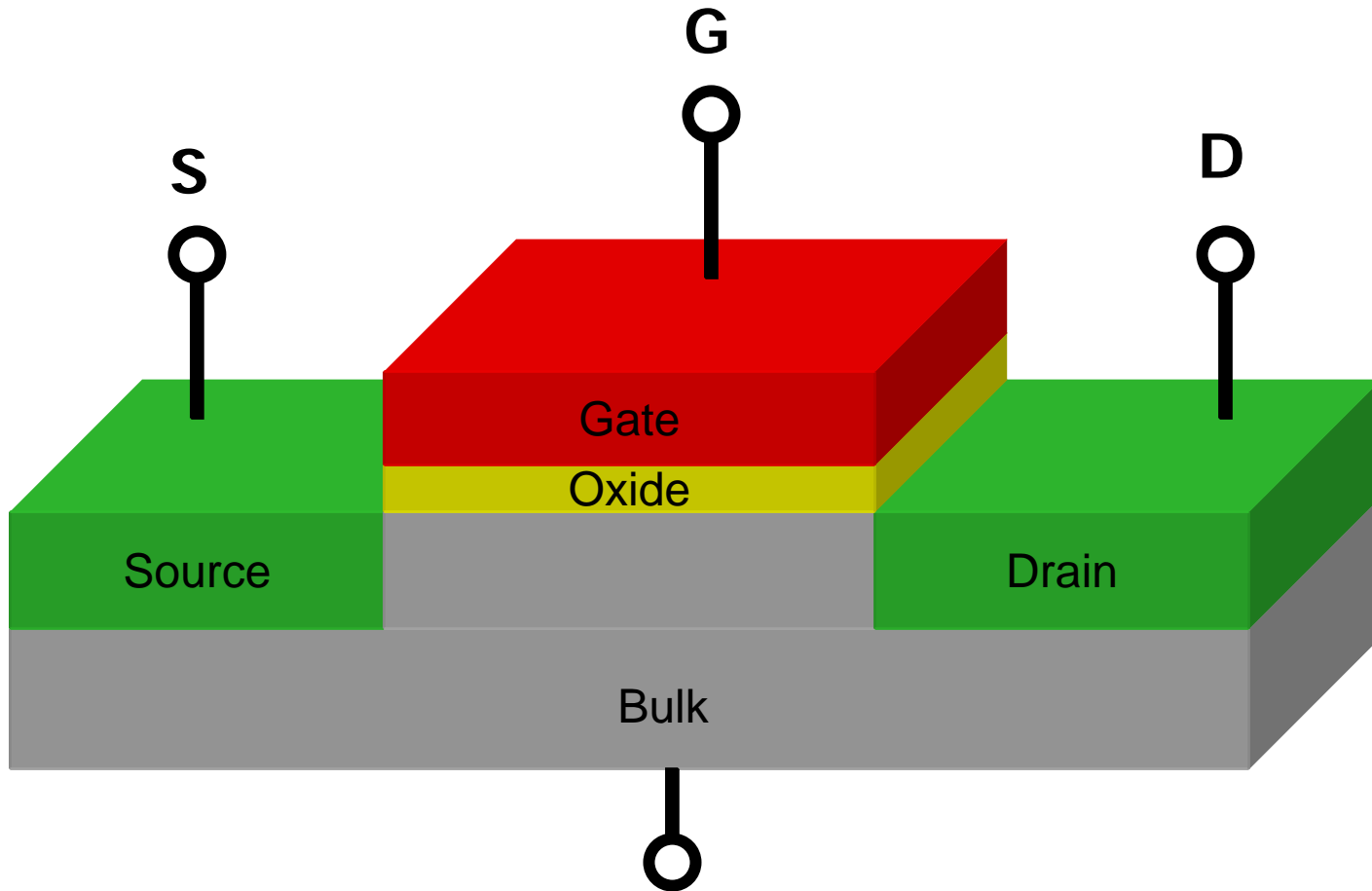


# Outline

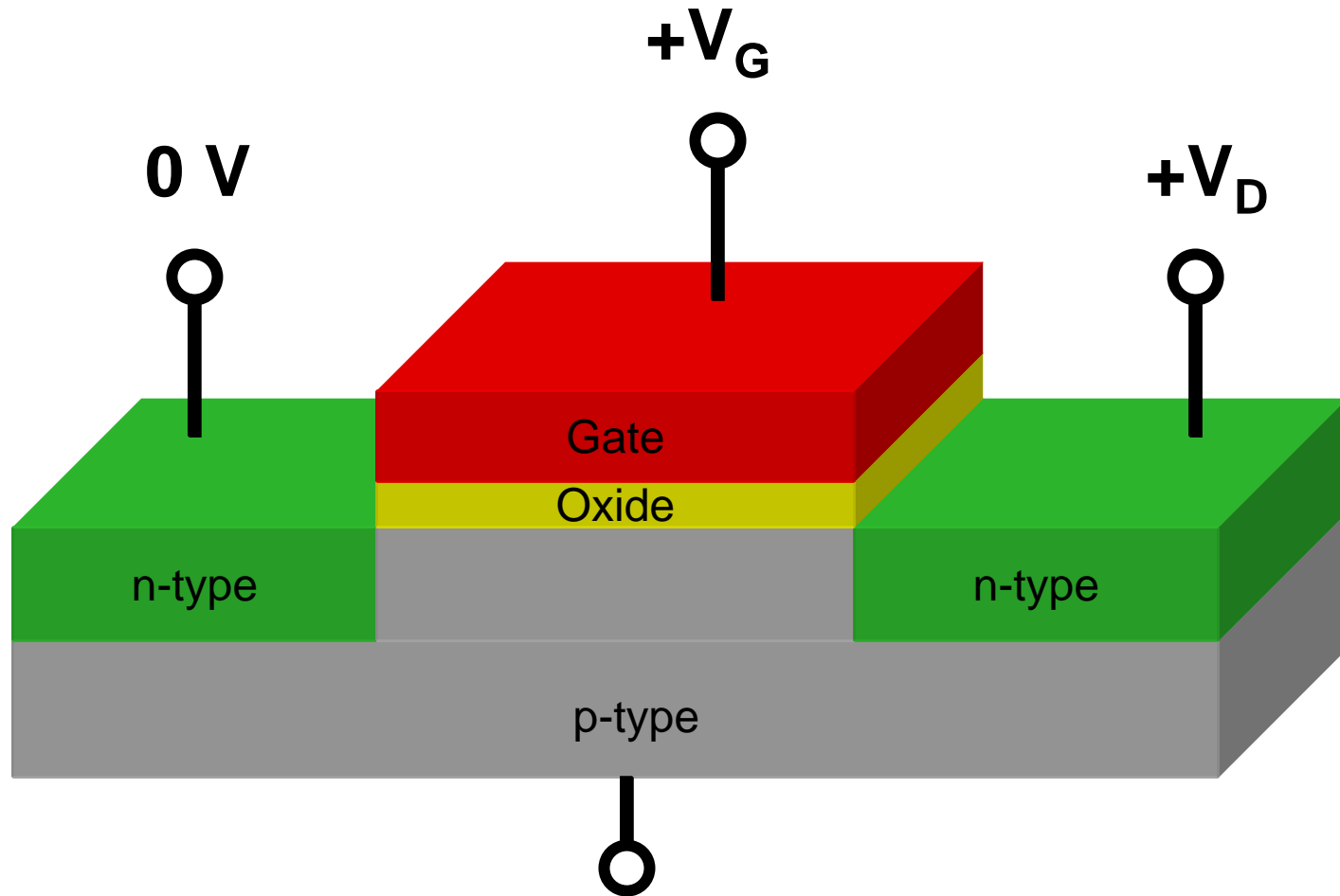
---

- The MOSFET Structure
- Semiconductor Doping
- The MOSFET as a Switch
- A MOSFET Process
- The MOS Capacitor Process
- Recommended reading
  - Plummer, Chapters 1 and 2

# MOSFET



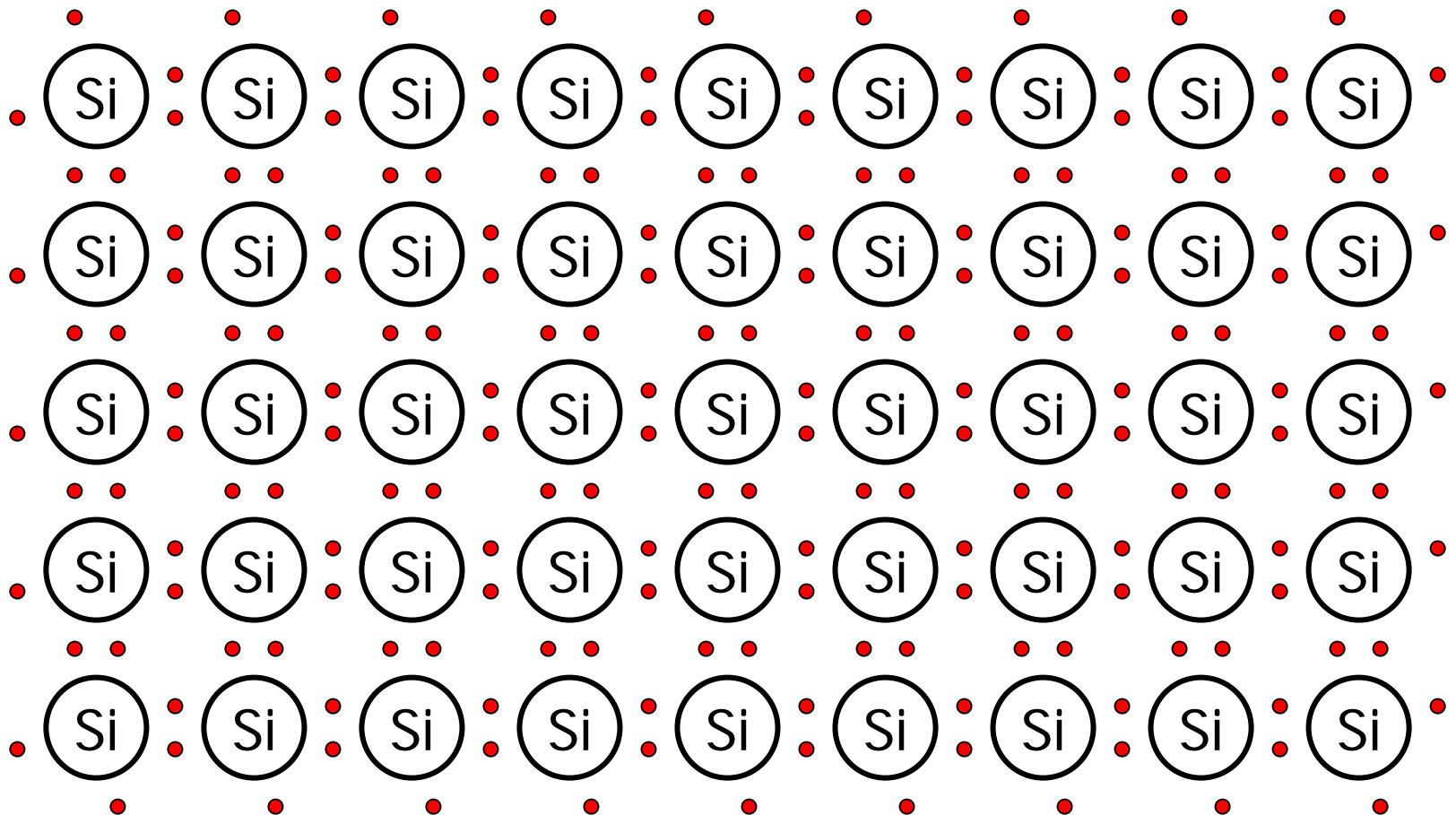
# N-Channel MOSFET



# A Word About Doping....

Silicon has four valence electrons

It covalently bonds with 4 adjacent atoms in the crystal lattice

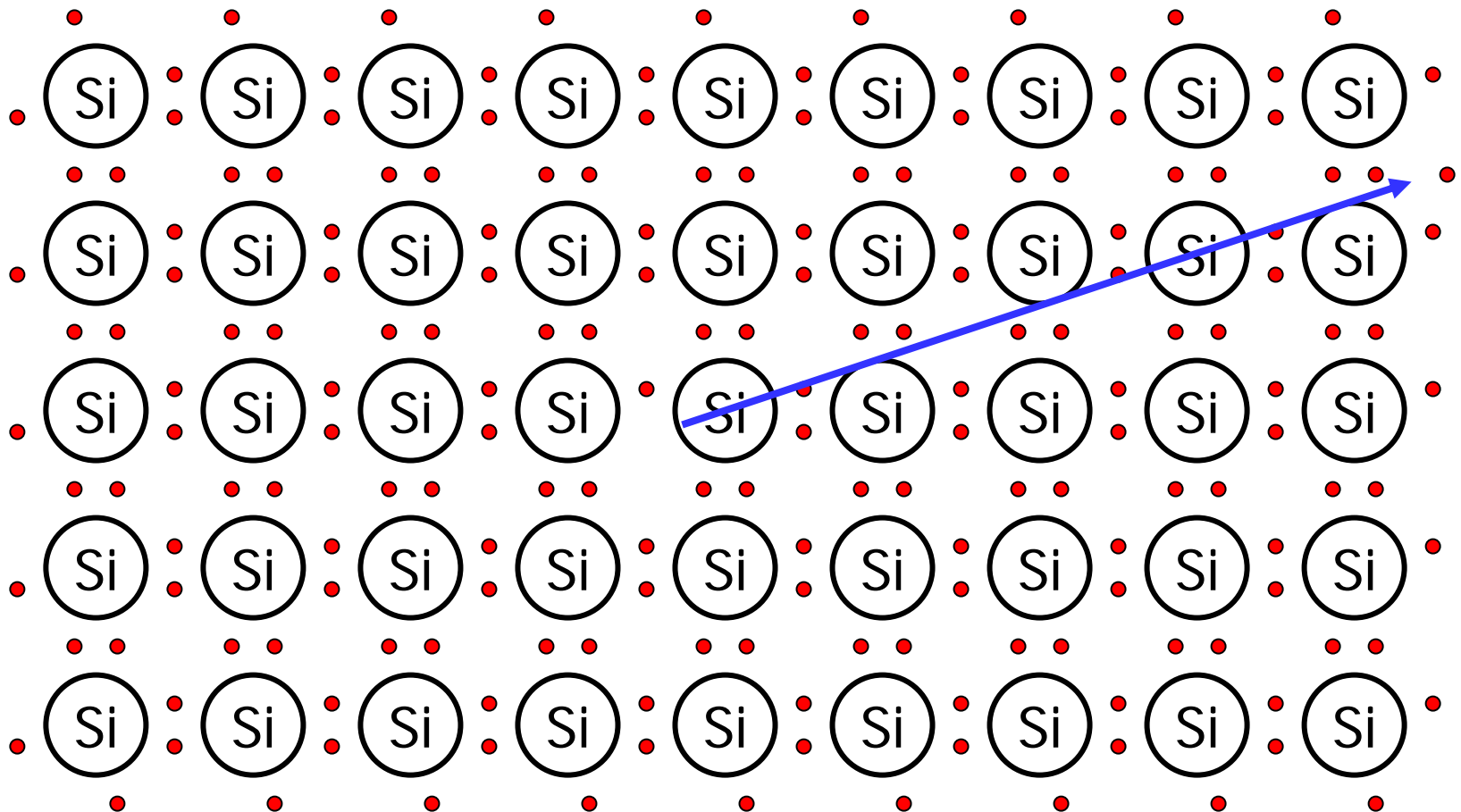


# Intrinsic Semiconductor

Increasing Temperature Causes Creation of Free Carriers

$10^{10} \text{ cm}^{-3}$  free carriers at 23°C (out of  $2 \times 10^{23} \text{ cm}^{-3}$ )

→ Intrinsic Conductivity

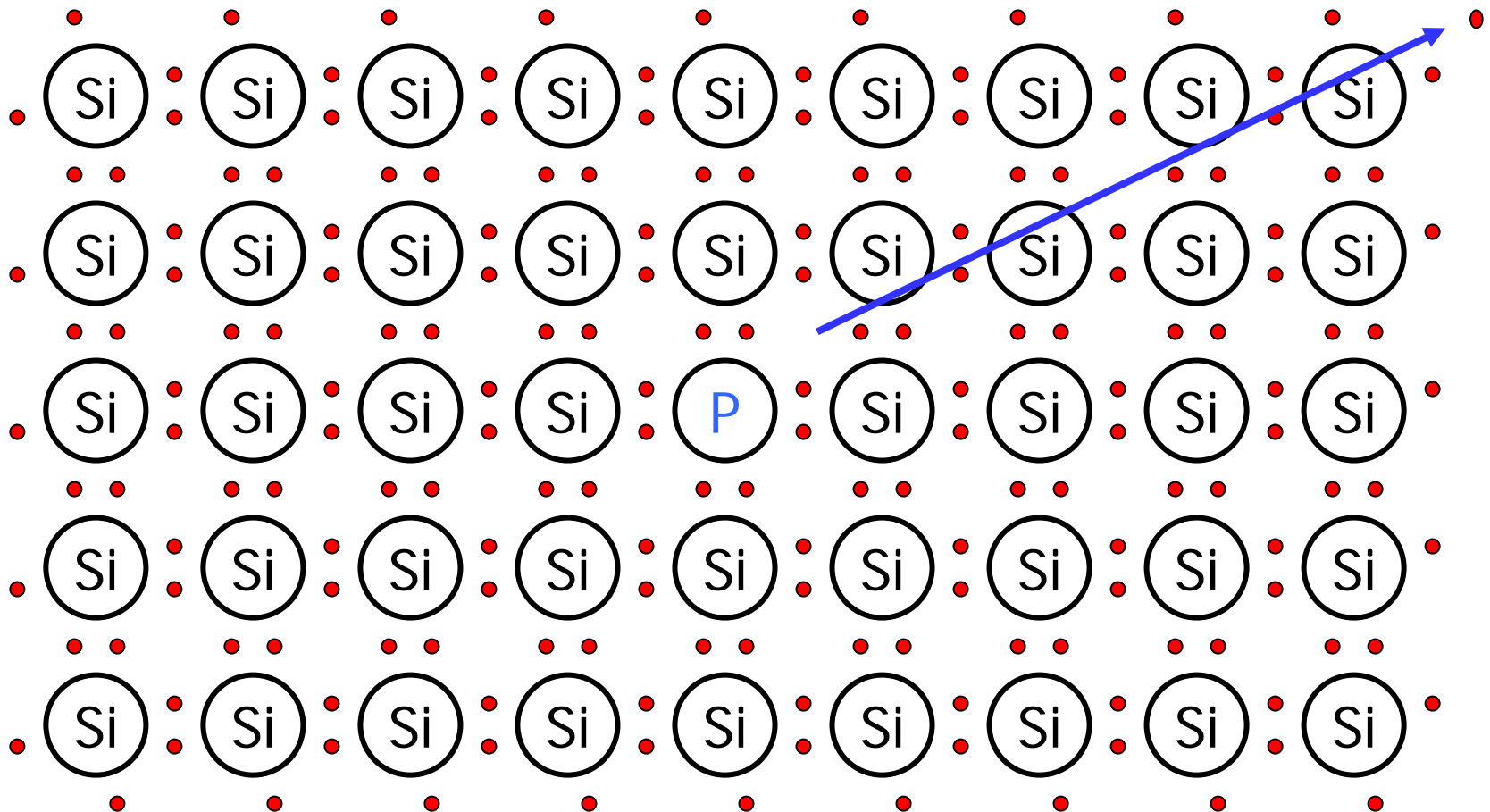


# N-type Doping

Phosphorus has 5 valence electrons

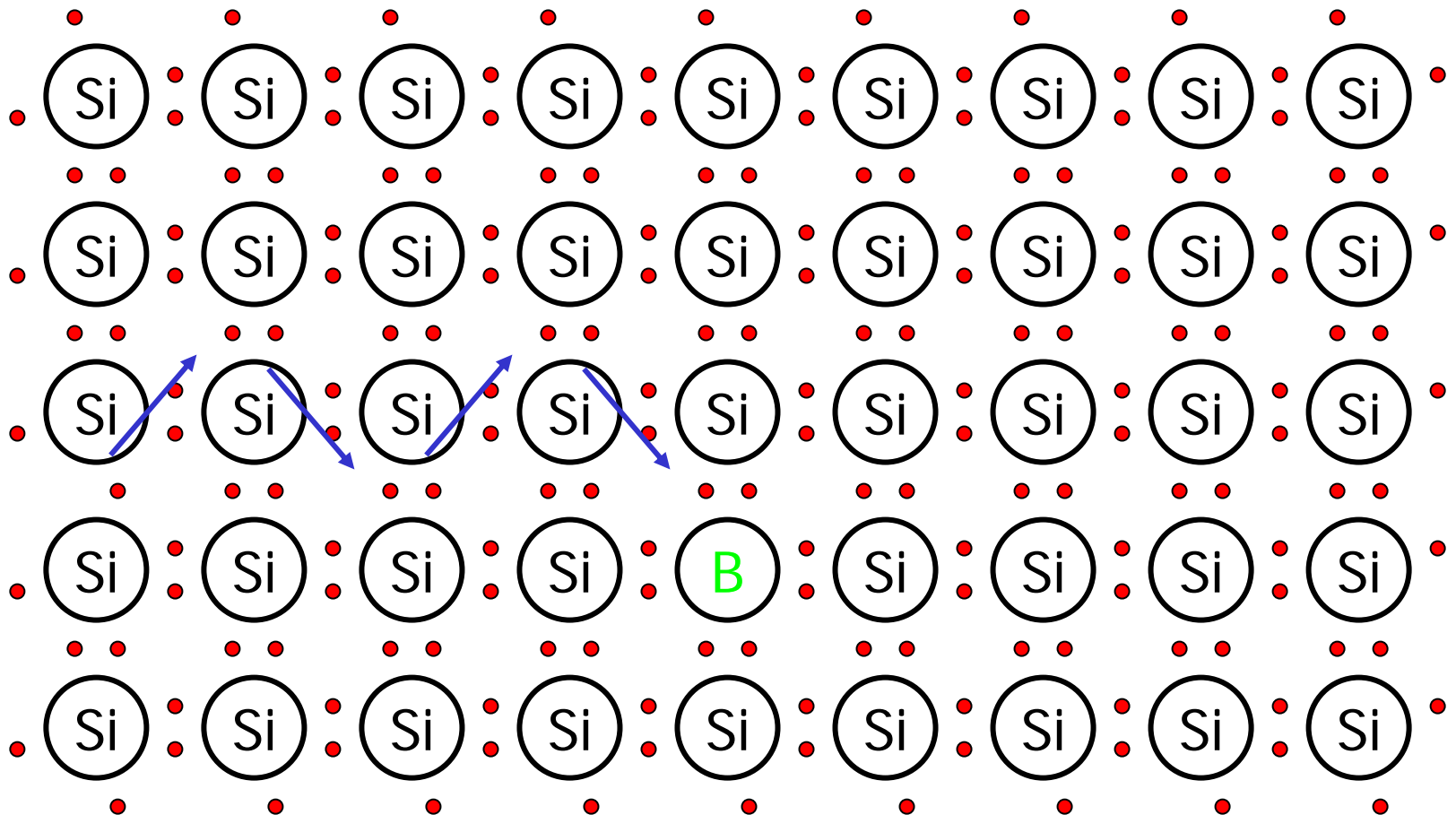
'Donates' one conduction electron – *n-type*

*Our substrate has  $10^{15} \text{ cm}^{-3}$  phosphorus (1 in  $10^8$ )*



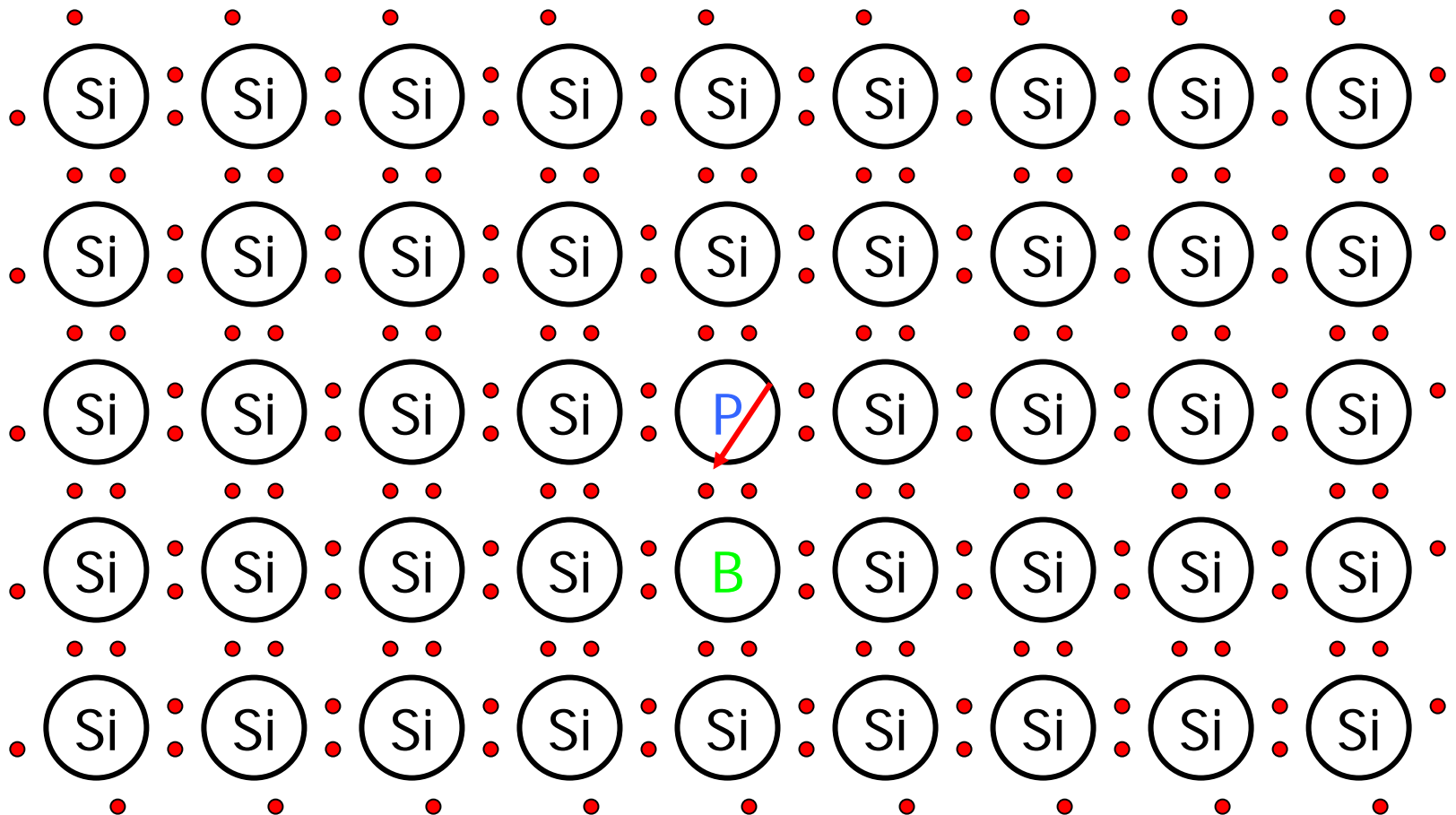
# P-type Doping

Boron has 3 valence electrons  
'Accepts' one electron from lattice  
Creates a 'hole' – *p-type*



# Counter Doping

The addition of one more B than P causes the doping type to change from n-type to p-type





# Counter Doping Process

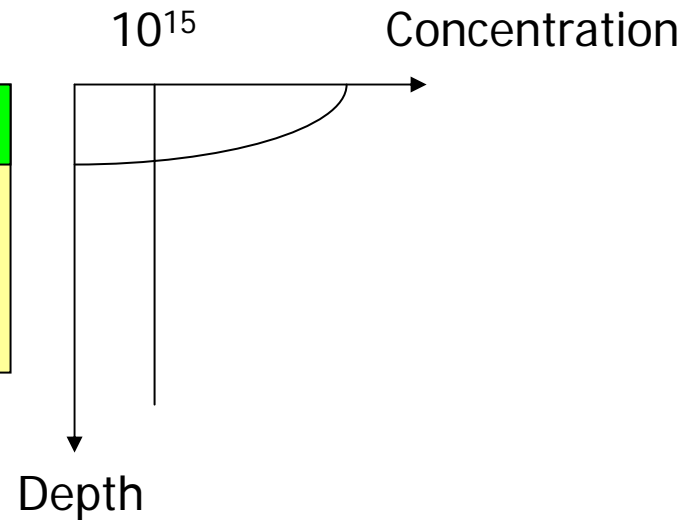
n-type ( $10^{15} \text{ cm}^{-3}$ )



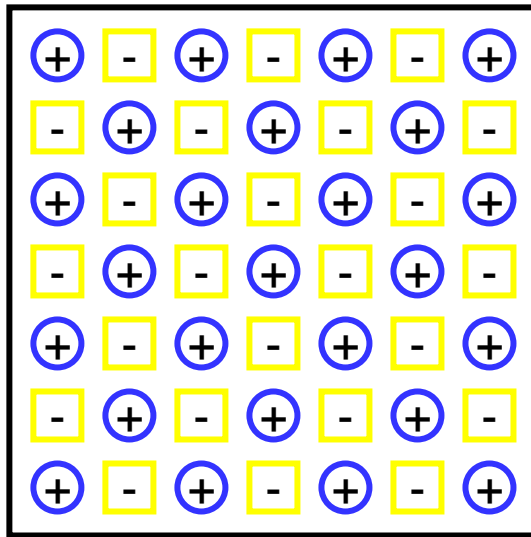
Implant Boron  
and Anneal

p-type ( $>10^{15} \text{ cm}^{-3}$ )

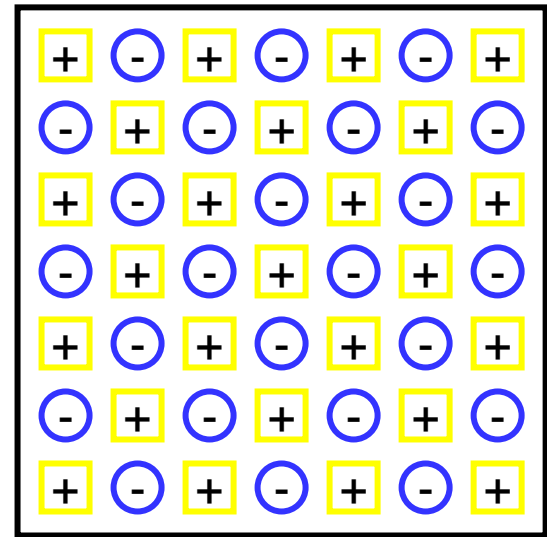
n-type ( $10^{15} \text{ cm}^{-3}$ )



# P/N Junction

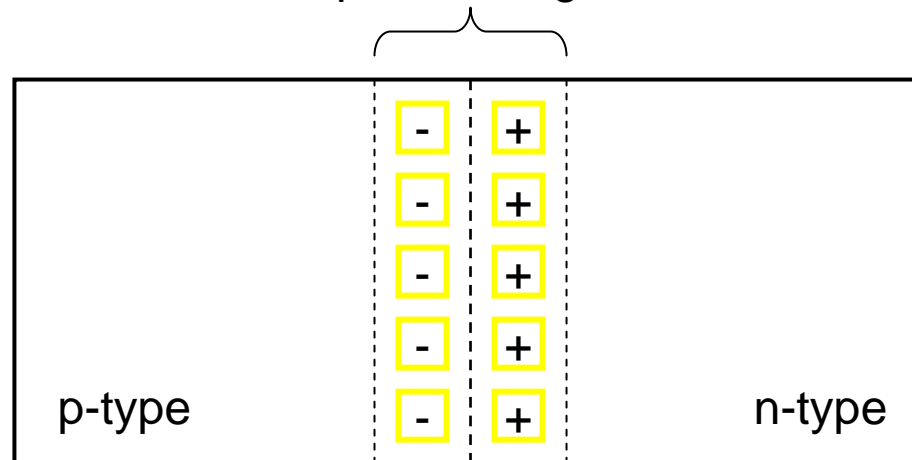


p-type

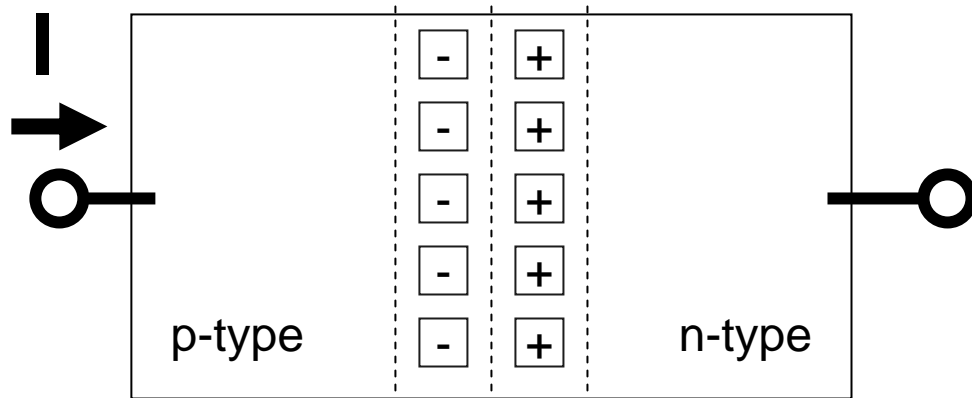


n-type

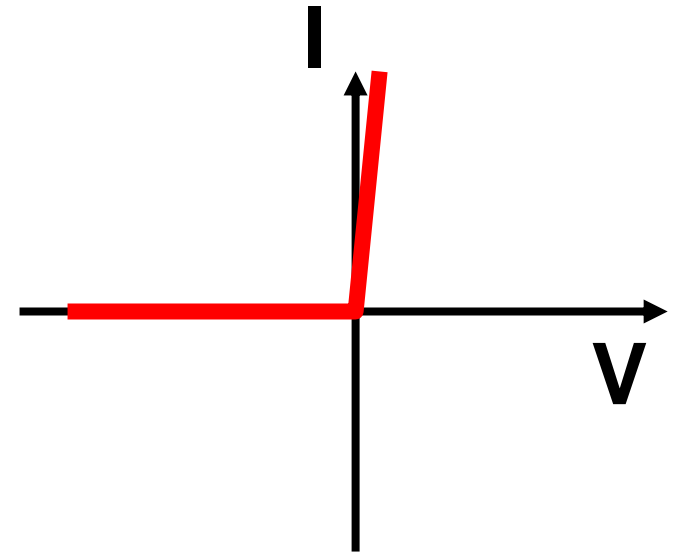
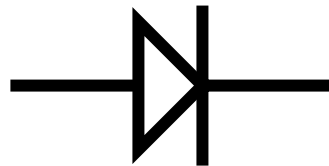
Depletion Region



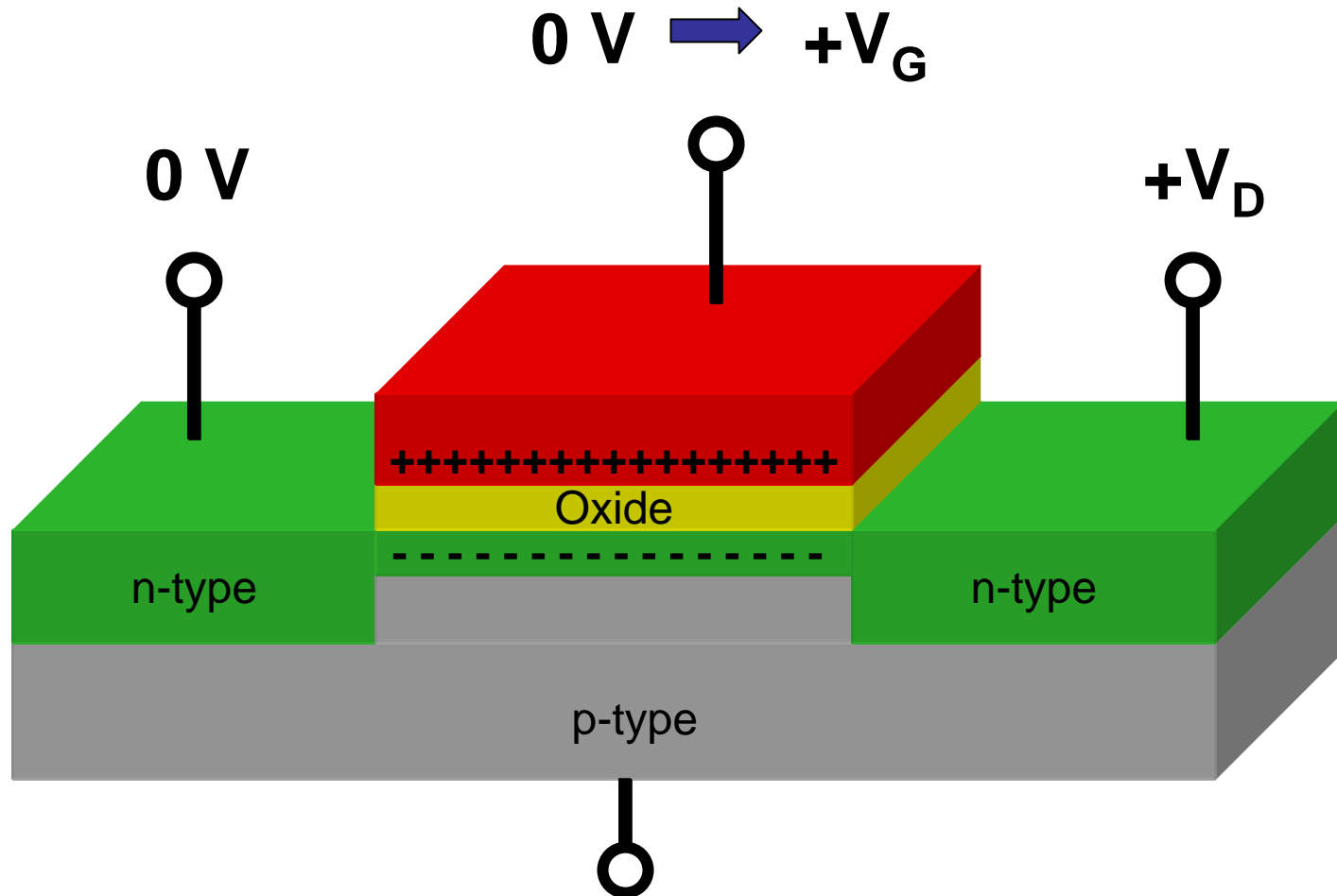
# P/N Junction - Diode



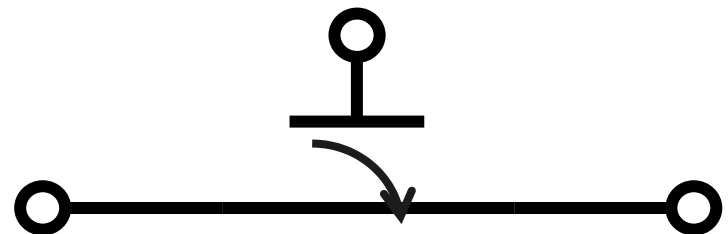
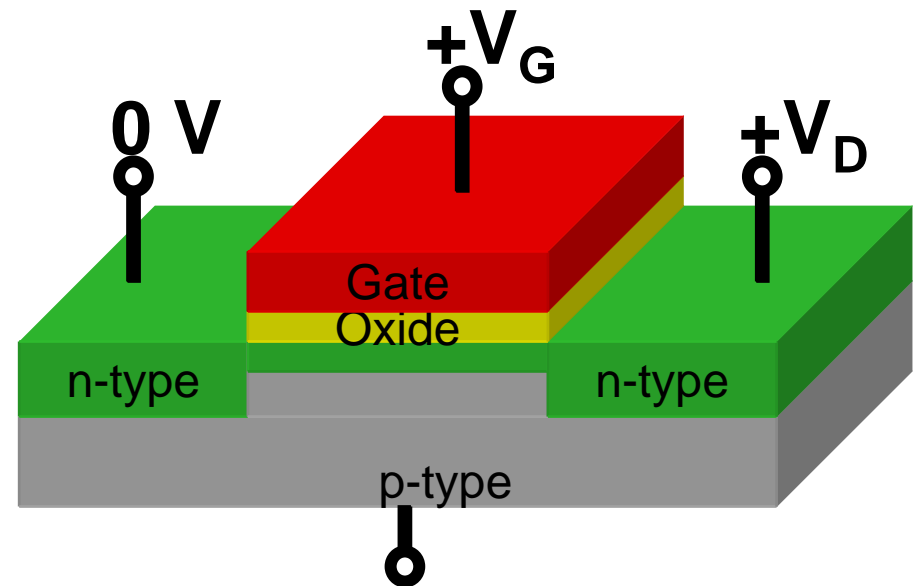
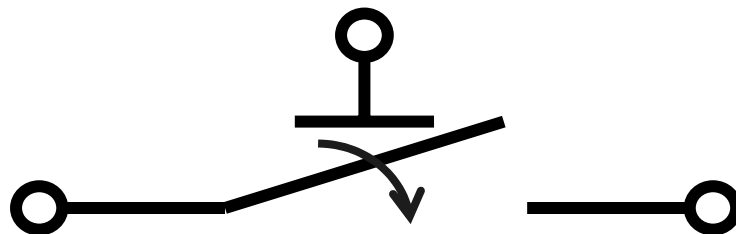
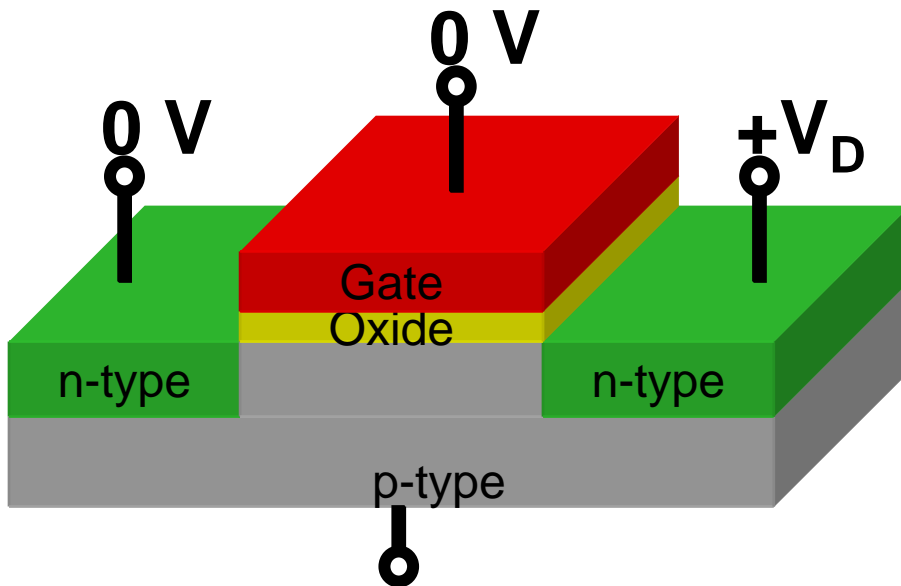
+ V -



# N-Channel MOSFET Operation

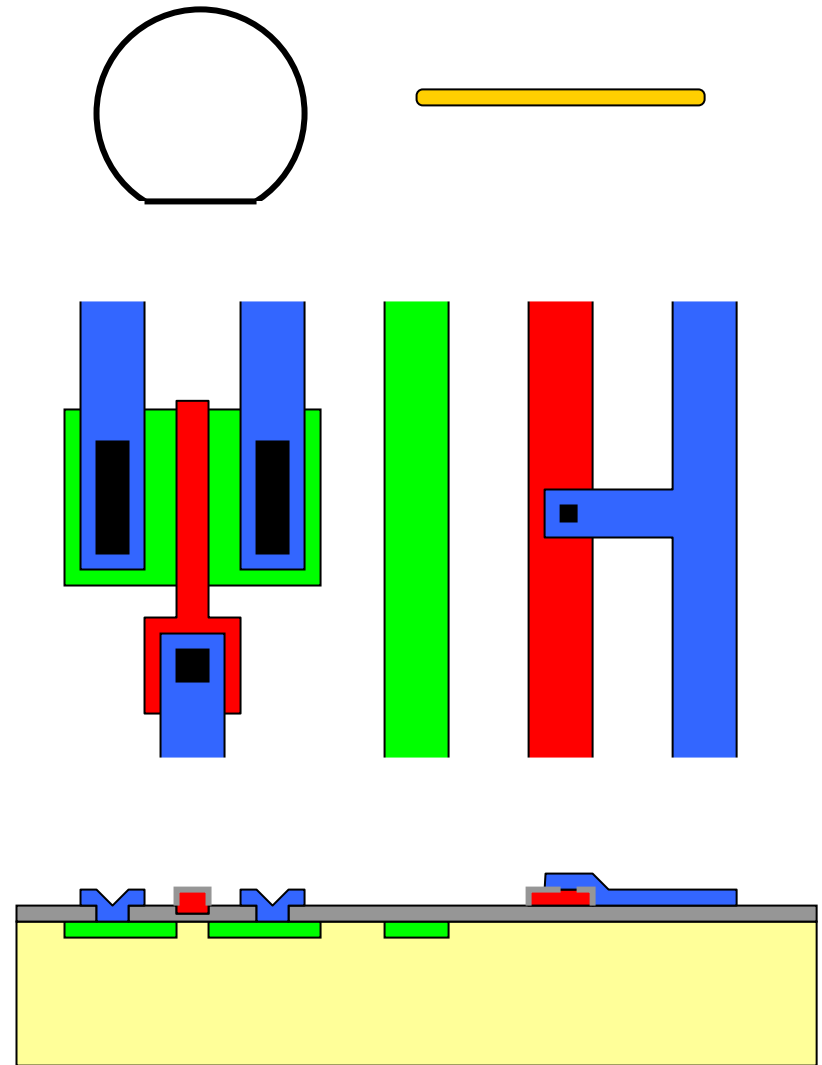


# MOSFET as a Switch



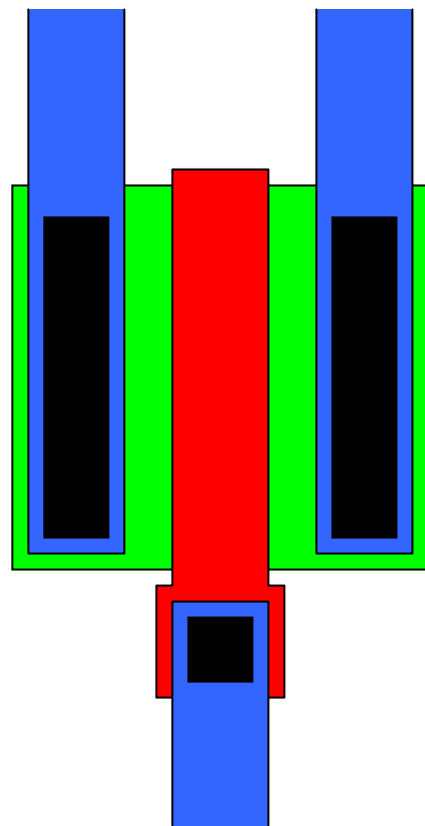
# Microfabricated Devices

- Starting Material
  - Single crystal silicon
- Mask Set
  - Contains x,y info  
(Top View)
- Process Sequence
  - Contains z info  
(Cross Section)

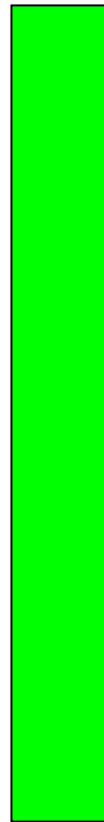


# Sample Mask Set

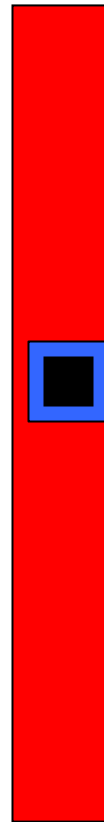
## ■ Four Levels (Masks)



Transistor  
(MOSFET)



Diffusion  
Resistor  
(Diode)



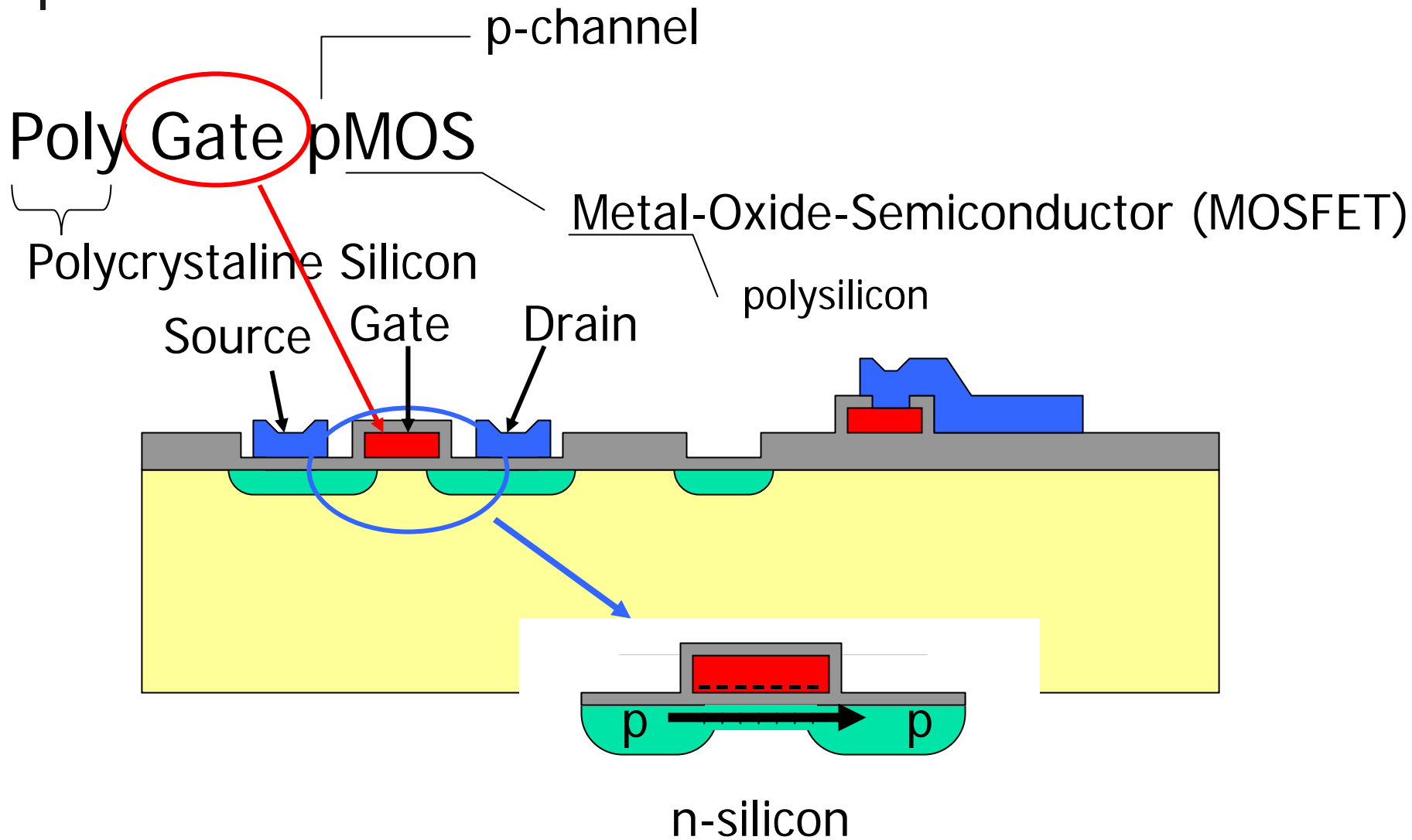
Polysilicon  
Resistor



Metal  
Resistor

<u>Mask</u>	<u>Definition</u>
 1	Active Area
 2	Polysilicon
 3	Contact Cuts
 4	Aluminum

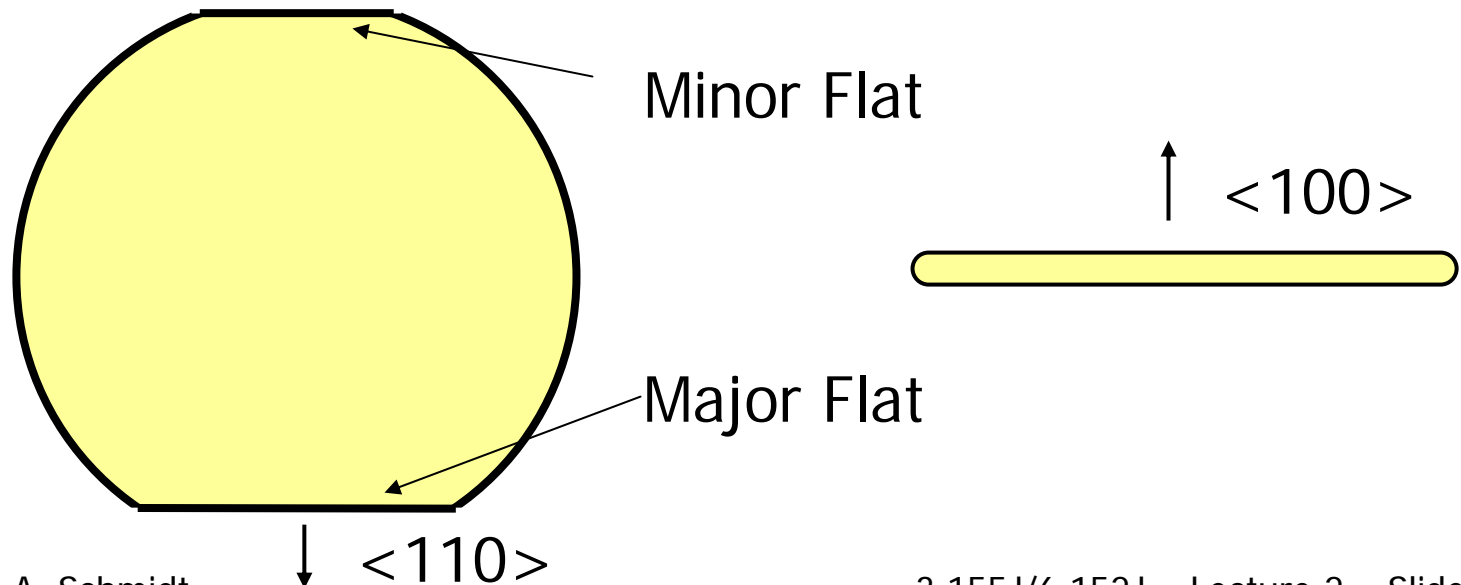
# Our Process





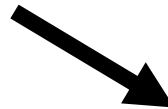
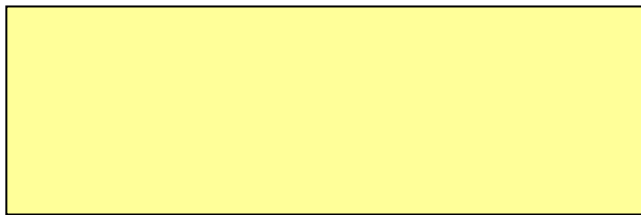
# Starting Material

- 6" (150mm) Diameter Silicon Wafer
  - 30 +/- 1 mil thick ( $\sim 750 \mu\text{m}$ )
  - n-type (doped with Phosphorus)
    - 1.5  $\Omega\text{-cm}$  resistivity ( $10^{15} \text{ cm}^{-3}$  Phos)
  - $\langle 100 \rangle$  crystal orientation



# FET Process Steps

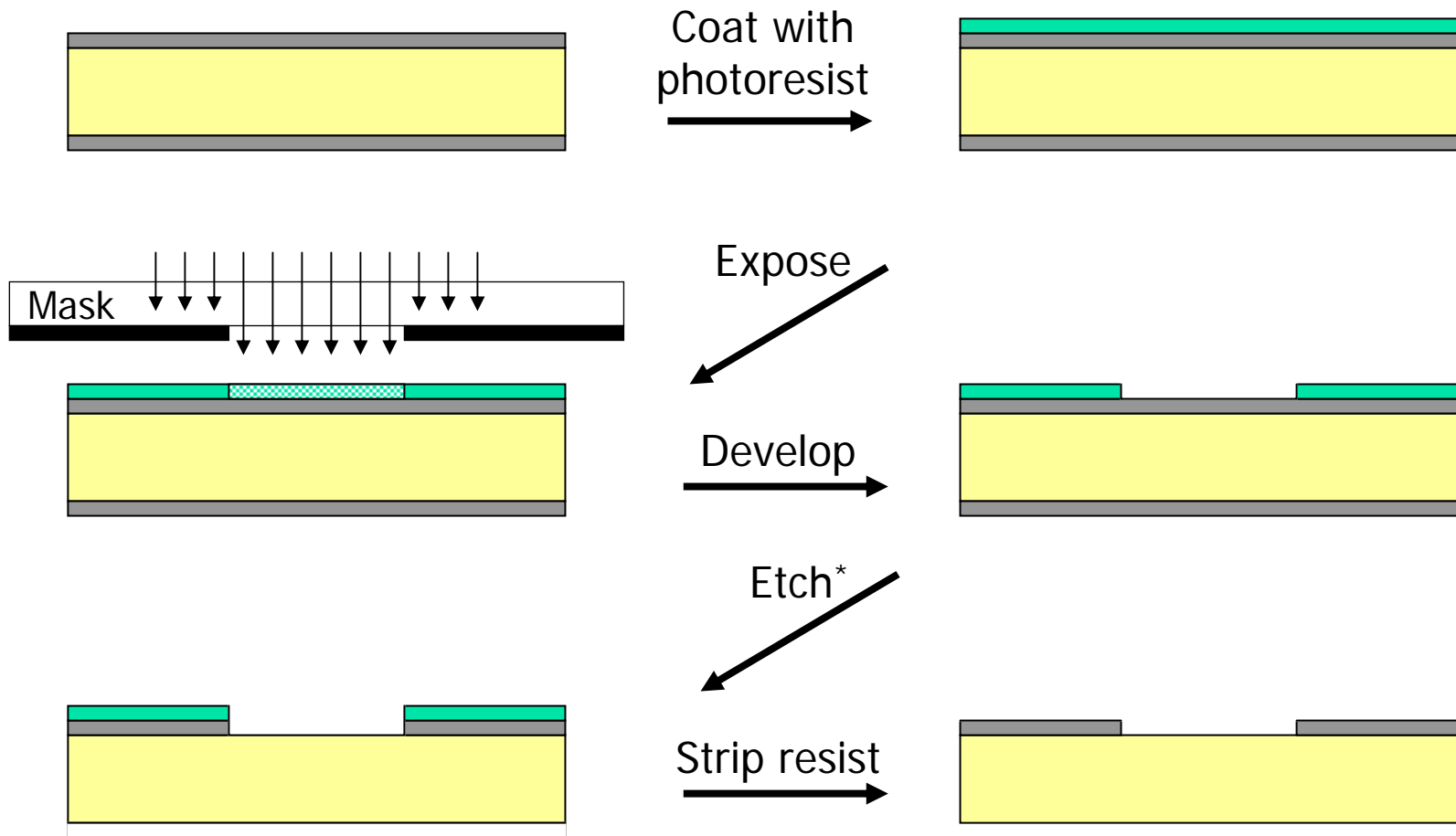
1. Characterize the wafer (resistivity, orientation, and type)
2. Grow 5000Å 'Field Oxide' for device isolation



Typically at 800-1100C for 1 hour in O<sub>2</sub> or steam

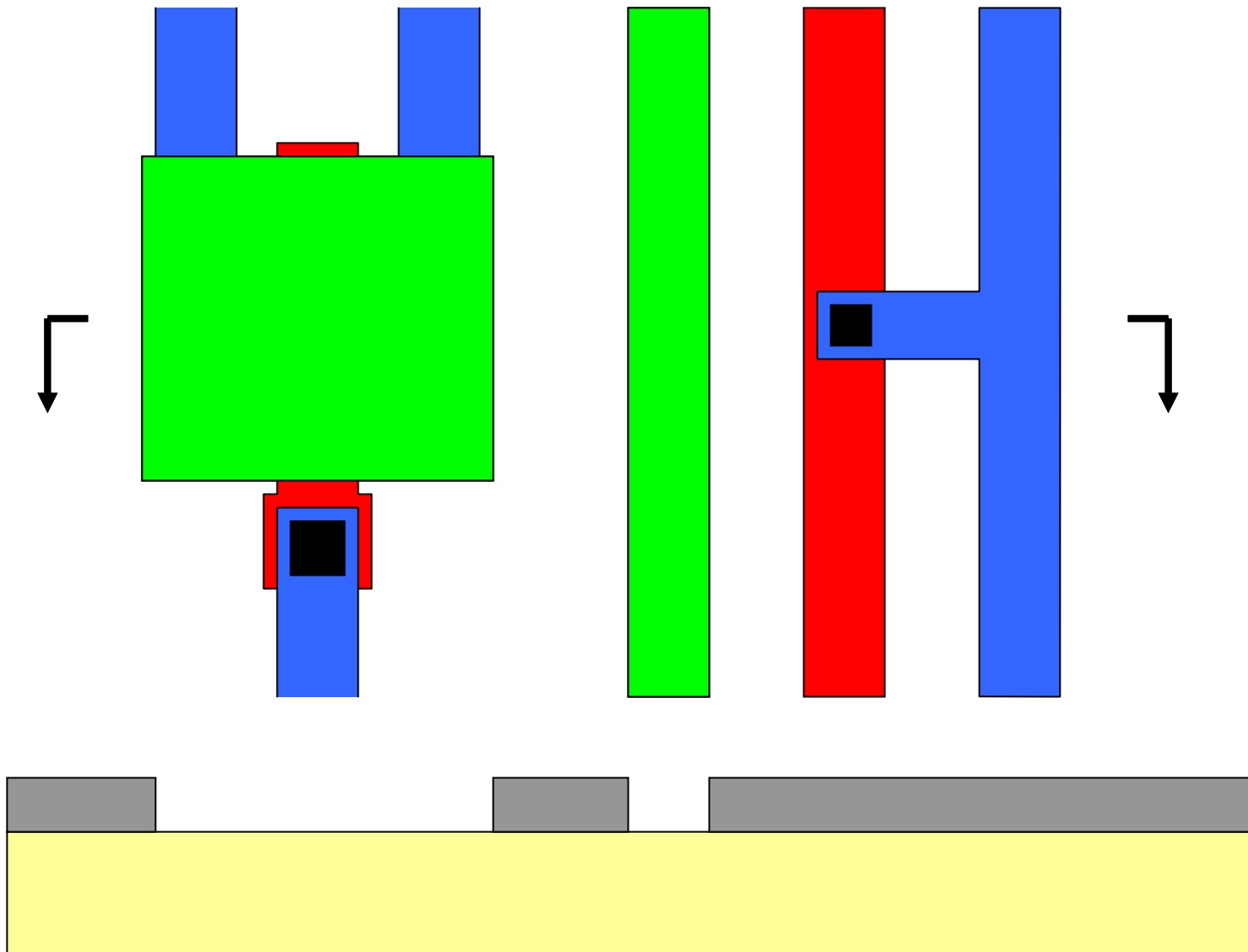
# Process Steps

## 3. Pattern Active Area (Mask #1)



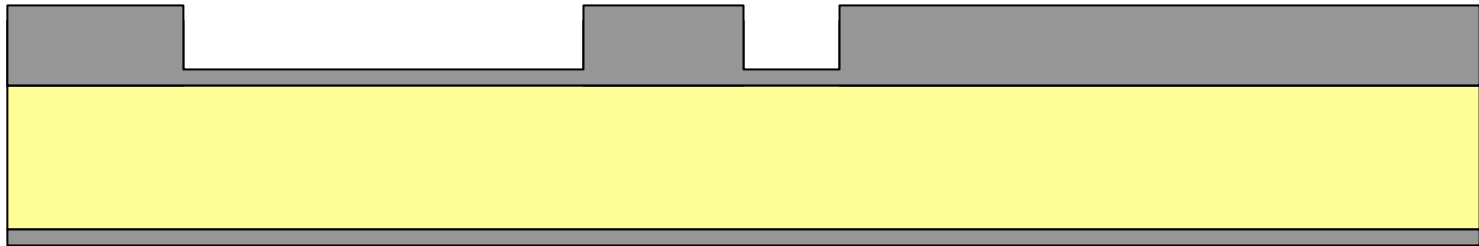
\*Wet etch

# Process Steps

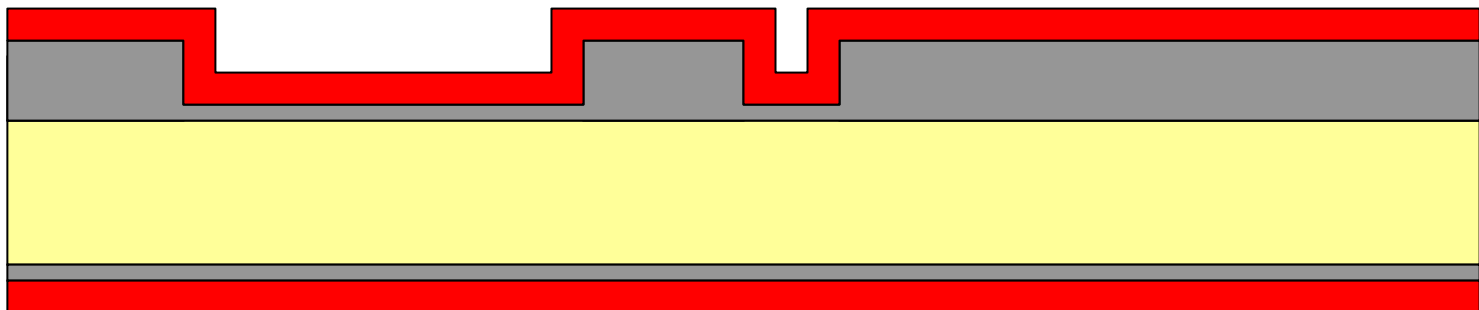


# Process Steps

## 4. Grow 500A Gate Oxide

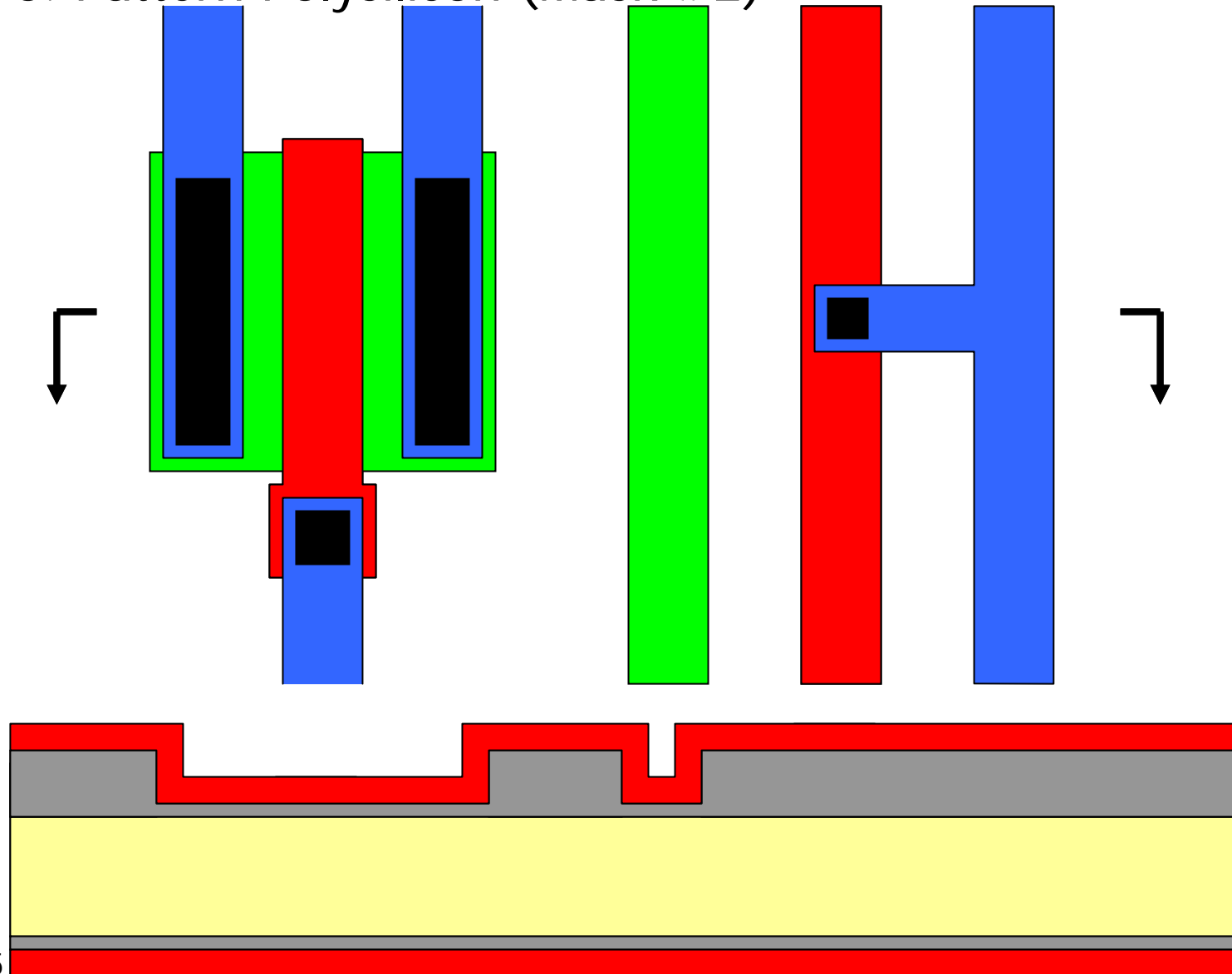


## 5. Deposit 5000A Polysilicon by LPCVD (low pressure chemical vapor deposition)



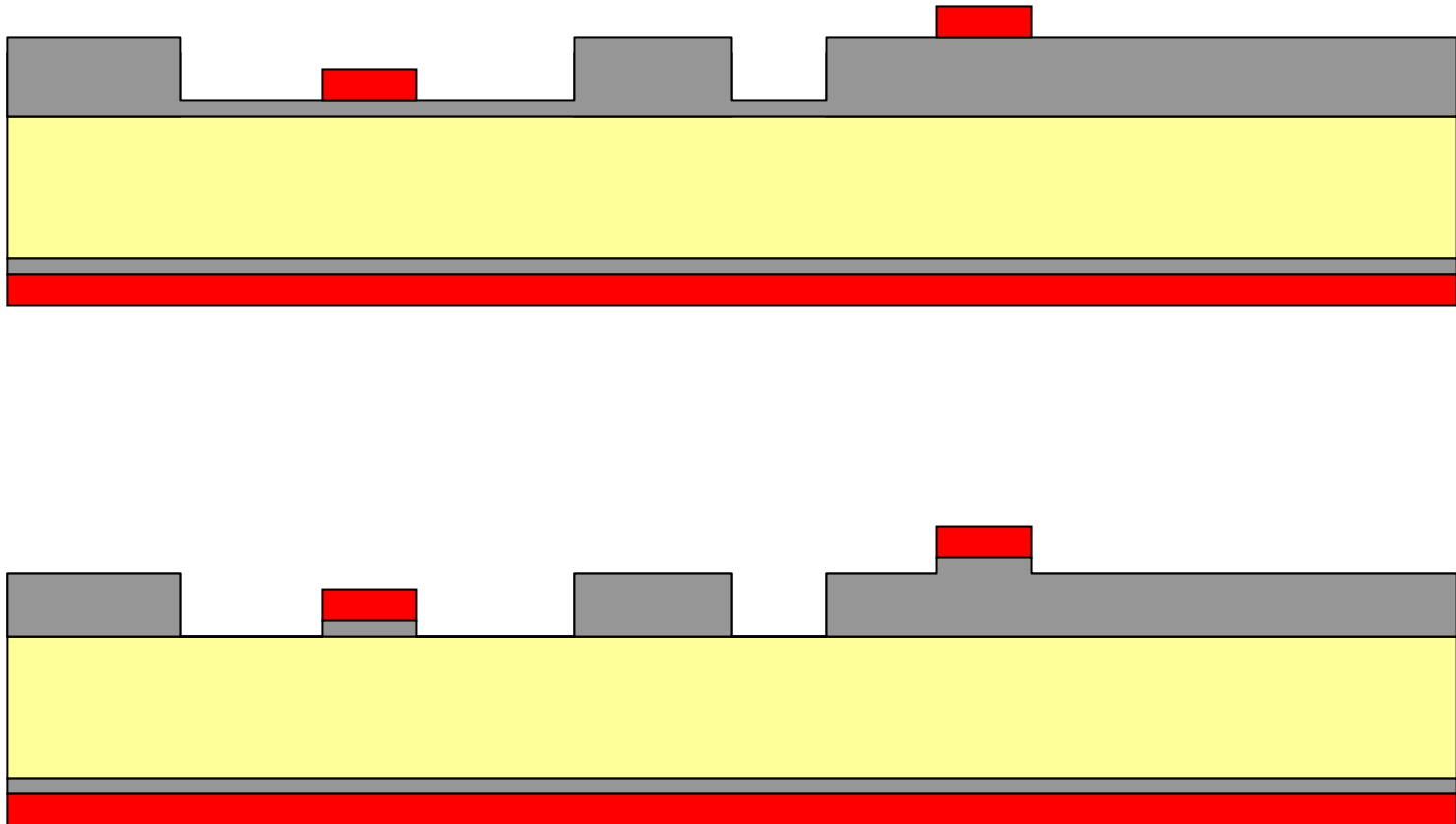
# Process Steps

## 6. Pattern Polysilicon (Mask #2)



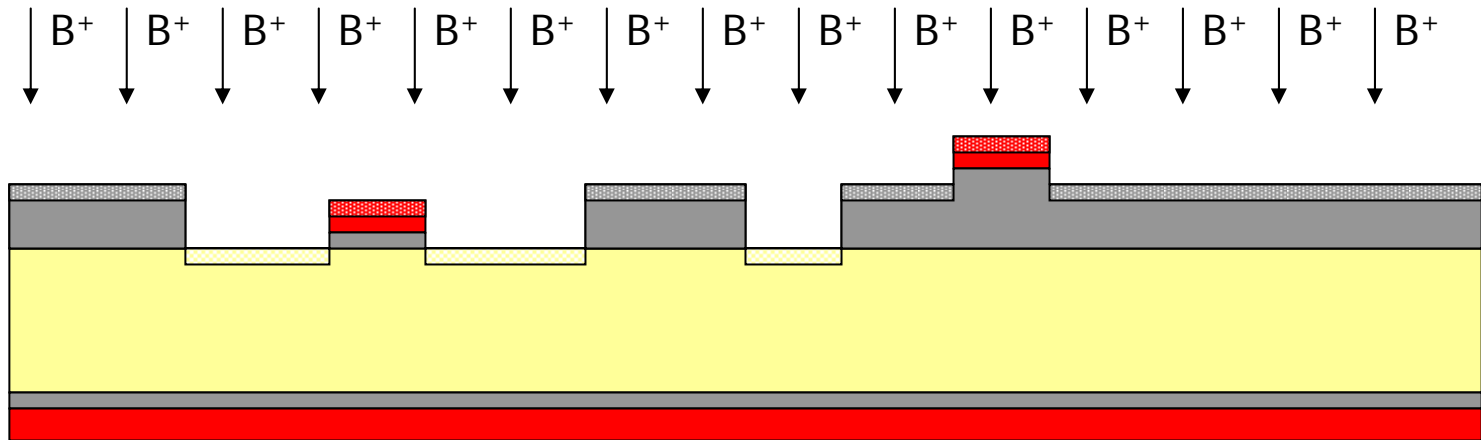
# Process Steps

## 7. Etch Gate Oxide

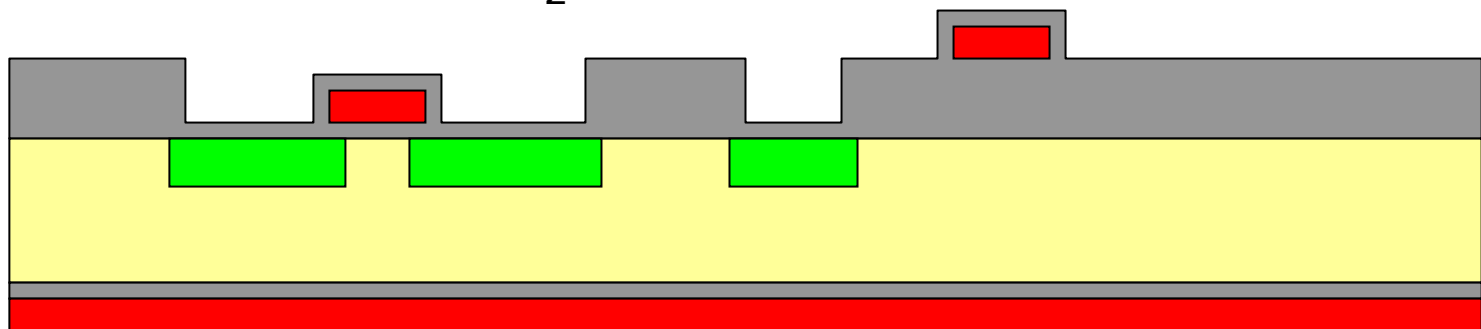


# Process Steps

## 8. Ion Implantation of Boron



## 9. Drive-In (950C in $O_2$ )

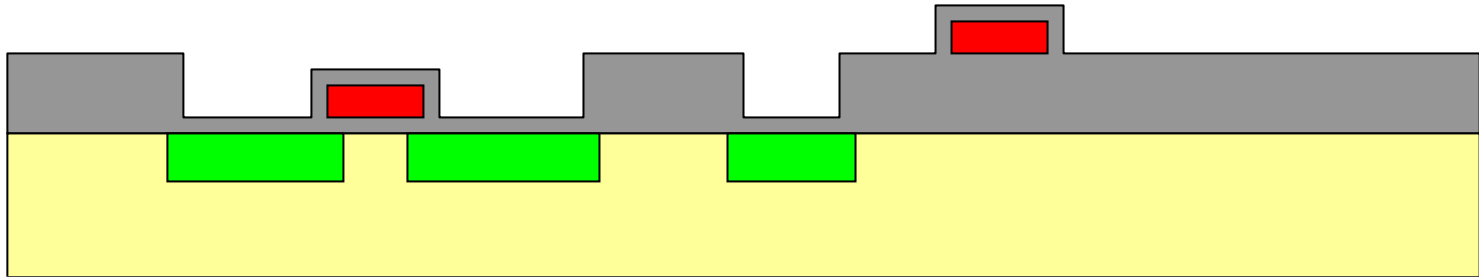


Note self alignment



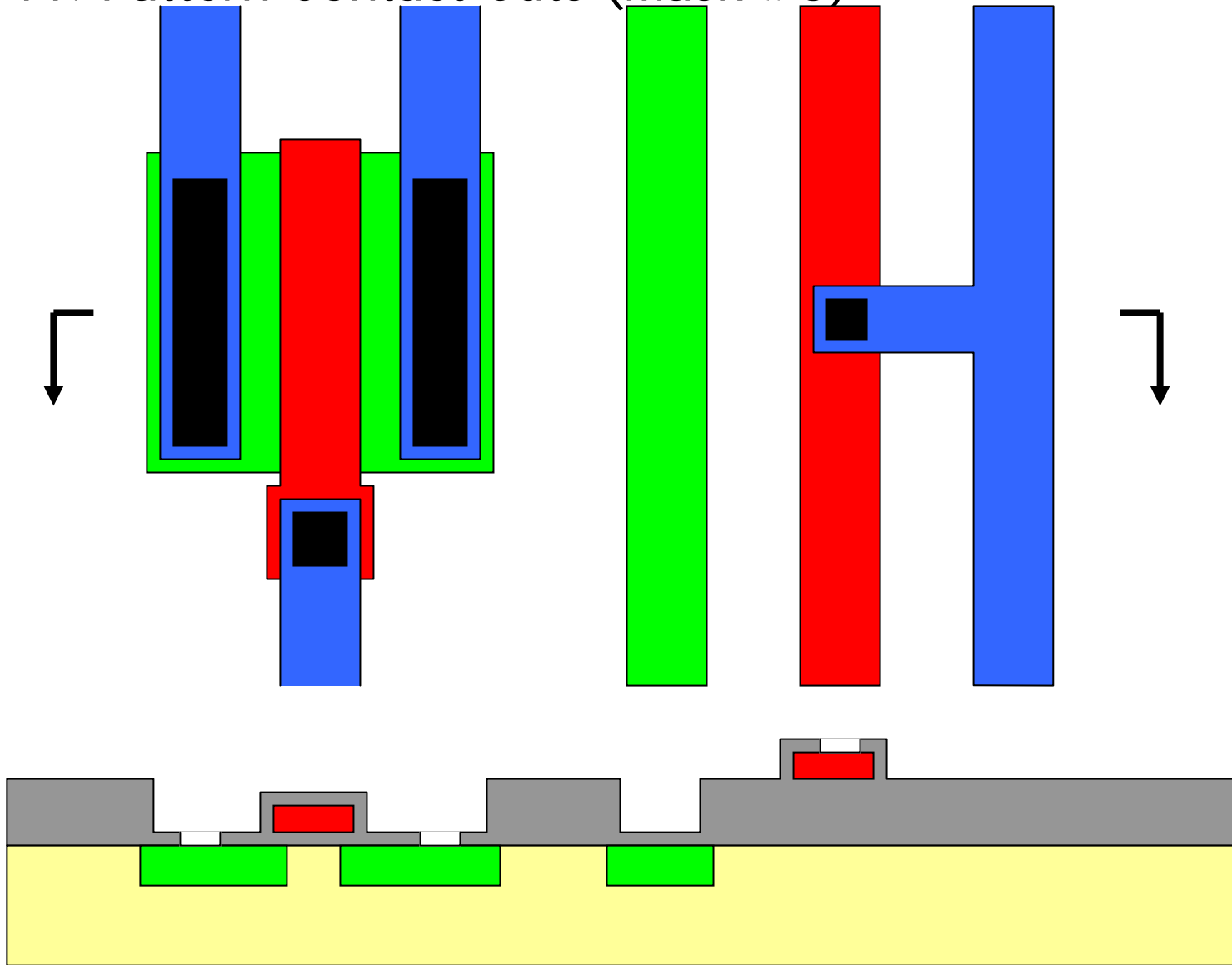
# Process Steps

## 10. Strip Backside



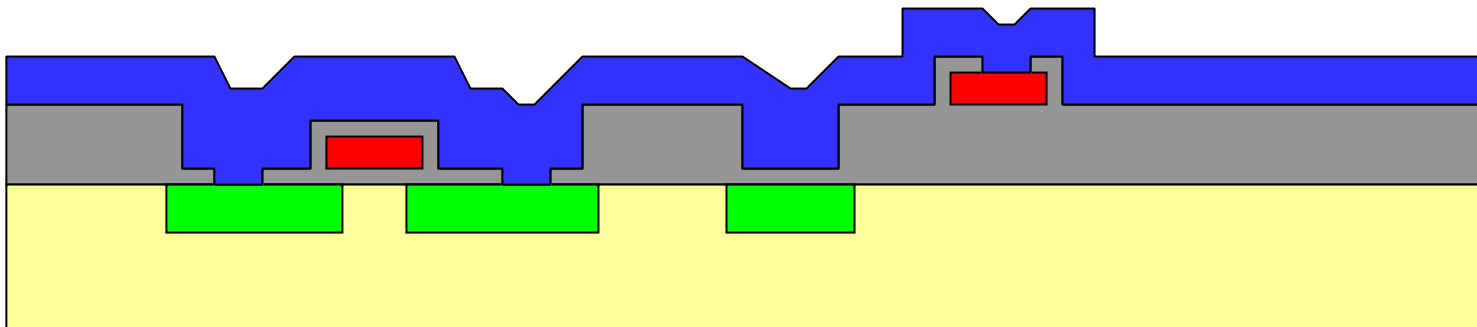
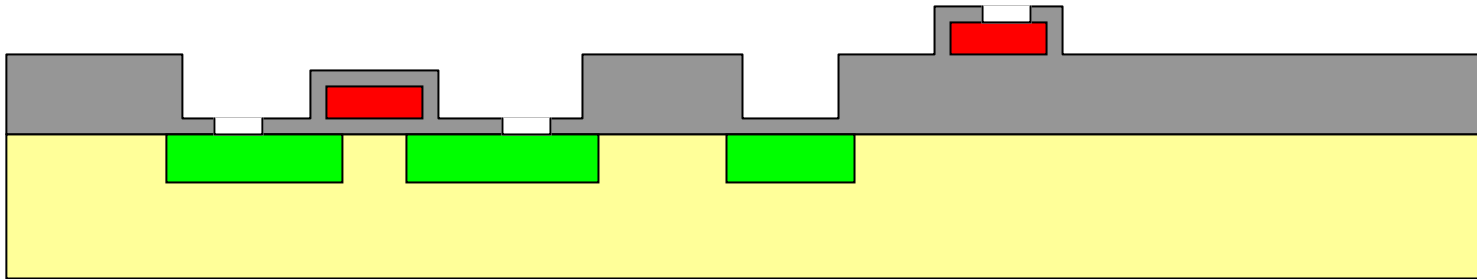
# Process Steps

## 11. Pattern Contact Cuts (Mask #3)



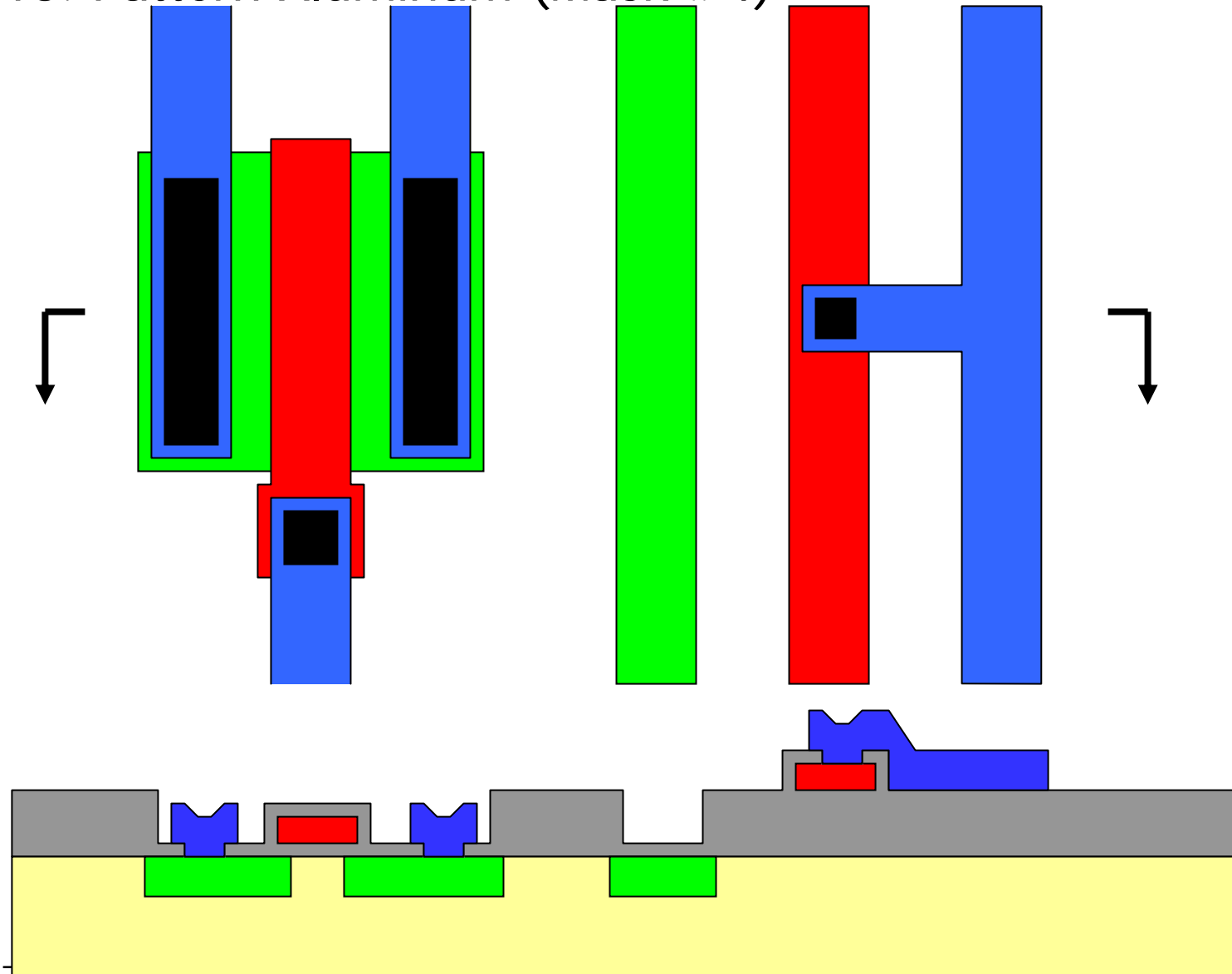
# Process Steps

## 12. Evaporate Aluminum



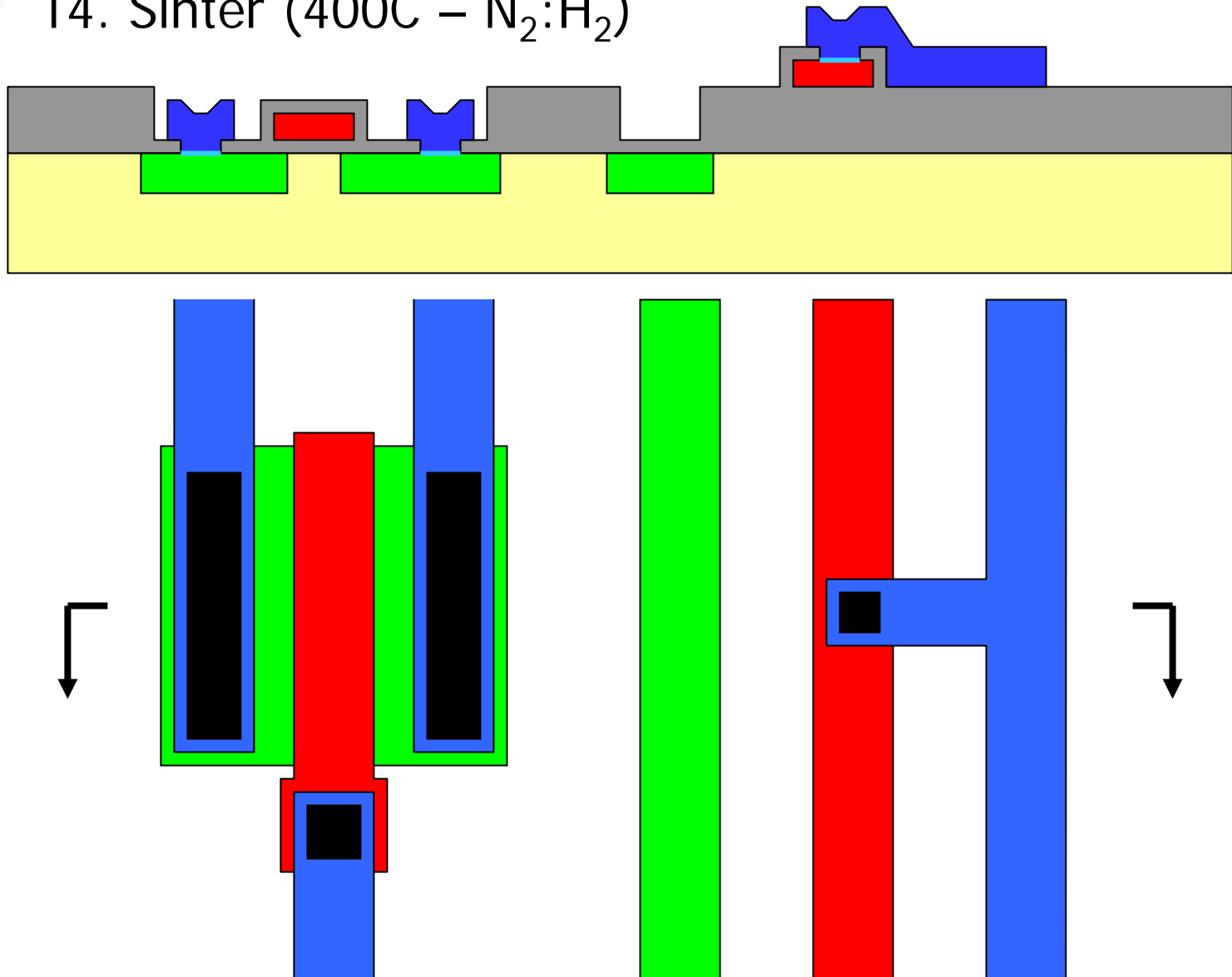
# Process Steps

## 13. Pattern Aluminum (Mask #4)



# Process Steps

## 14. Sinter (400C – N<sub>2</sub>:H<sub>2</sub>)



# Process Results

## ■ The Four Mask Process Yields

### ■ Resistors

- Metal
- Polysilicon
- Diffusion

### ■ Capacitors

- Metal-Silicon
- Metal-Polysilicon
- Polysilicon-Silicon
  - Gate Oxide
  - Field Oxide

### ■ Diode

### ■ MOSFET

### ■ Bipolar Junction Transistor (low quality)

